



Cs-Corrected TEM Demonstration

RSC Host: Dr. Nick Rudawski

Presenter: Dr. Jan Ringnalda

Affiliation: Thermo Fisher Scientific

Time: 12:30 PM – 1:00 PM EST

Zoom: [Click here to join!](#)

Description

Please join Jan as he demonstrates the ability for the new TEM to find an area of interest, tilt to the required zone axis, take a high resolution TEM image and then switch to STEM mode to then take a high resolution STEM image and perform an EDS analytical line profile; illustrating the high spatial resolution analytical capability of the system.

More about the presenter

Presenter Bio: Jan got his PhD From Liverpool University in 1993, after which he did a postdoctoral study at The Ohio State University. He has been involved with Transmission Electron Microscopy work since 1984. His background includes failure analysis, materials characterization using EDS, EELS and imaging using TEM and STEM techniques. In his present position with Thermo Fisher Scientific, he provides technical sales support, presents scientific results at conferences and still participates in research with students at The Ohio State University to make sure the systems fulfill the requirements of a state-of-the-art research lab.

FEI Talos F200i S/TEM: <https://rsc.aux.eng.ufl.edu/ccb/resource.asp?id=177>

